Search Notes			

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/015,497	LIN ET AL.	
Examiner	Art Unit	-
Kerri M. Dyke	2667	

	SEAR	CHED	
Class	Subclass	Date	Examiner
370	351, 389, 392, 400, 422	2/28/2006	KMD
709	242	2/28/2006	KMD
711	1, 200	2/28/2006	KMD
711	202	2/28/2006	KMD

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
East, IEEE - see printouts	2/28/2006	KMD
Combined citation search of 5,940,596	2/28/2006	KMD
Combined citation search of 5,754,791 and 6,606,322	3/1/2006	KMD